

STP36NF03L

N-CHANNEL 30V - 0.015 Ω - 40A TO-220 LOW GATE CHARGE STripFET™II POWER MOSFET

PRELIMINARY DATA

TYPE	V _{DSS}	R _{DS(on)}	I _D
STP36NF03L	30 V	<0.02Ω	36 A

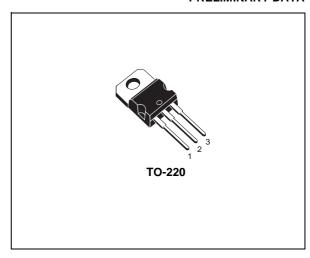
- TYPICAL $R_{DS}(on) = 0.015 \Omega$
- TYPICAL Q_g = 18 nC @ 10V
- OPTIMAL R_{DS(on)} x Qg TRADE-OFF
- CONDUCTION LOSSES REDUCED
- SWITCHING LOSSES REDUCED

DESCRIPTION

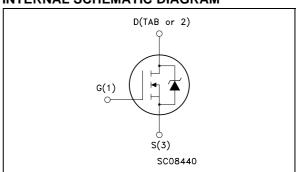
This application specific Power MOSFET is the third genaration of STMicroelectronis unique "Single Feature SizeTM" strip-based process. The resulting transistor shows the best trade-off between on-resistance and gate charge. When used as high and low side in buck regulators, it gives the best performance in terms of both conduction and switching losses. This is extremely important for motherboards where fast switching and high efficiency are of paramount importance.

APPLICATIONS

 SPECIFICALLY DESIGNED AND OPTIMISED FOR HIGH EFFICIENCY CPU CORE DC/DC CONVERTERS



INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	30	V
V _{GS}	Gate- source Voltage	± 18	V
ID	Drain Current (continuous) at T _C = 25°C	36	A
I _D	Drain Current (continuous) at T _C = 100°C	25	A
I _{DM} (●)	Drain Current (pulsed)	144	A
P _{tot}	Total Dissipation at T _C = 25°C	75	W
	Derating Factor	0.5	W/°C
T _{stg}	Storage Temperature	-65 to 175	°C
Tj	Max. Operating Junction Temperature	175	°C

^(•) Pulse width limited by safe operating area

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THERMAL DATA

	,	Thermal Resistance Junction-case Thermal Resistance Junction-ambient Maximum Lead Temperature For Soldering Purpose	Max Max Typ	2 62.5 300	°C/W °C/W °C	
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ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A$ $V_{GS} = 0$	30			٧
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating T_{C} = 125°C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 18V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	1			V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V V _{GS} = 5 V	I _D = 18 A I _D = 9 A		0.015 0.026	0.020 0.035	Ω Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	V _{DS} >I _{D(on)} xR _{DS(on)max} I _D =18 A		20		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$		750 270 60		pF pF pF

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ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{array}{ccc} V_{DD} = 15 \text{ V} & I_D = 18 \text{ A} \\ R_G = 4.7 \ \Omega & V_{GS} = 4.5 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{array}$		16 200		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} =24 V I _D =32 A V _{GS} =10V		18 3 5	21	nC nC nC

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(Off)} t _f	Turn-off Delay Time Fall Time	$\begin{array}{ccc} V_{DD} = 15 \text{ V} & I_D = 18 \text{ A} \\ R_G = 4.7\Omega, & V_{GS} = 4.5 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{array}$		35 40		ns ns

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (•)	Source-drain Current Source-drain Current (pulsed)				36 144	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 36 A V _{GS} = 0			1.5	V
t _{rr} Q _{rr} IRRM	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$\begin{split} I_{SD} = 36 \text{ A} & \text{di/dt} = 100 \text{A/}\mu\text{s} \\ V_{DD} = 15 \text{ V} & T_j = 150 ^{\circ}\text{C} \\ \text{(see test circuit, Figure 5)} \end{split}$		50 80 2		ns nC A

^(*)Pulsed: Pulse duration = 300 µs, duty cycle 1.5 %.

(•)Pulse width limited by safe operating area.

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Fig. 1: Unclamped Inductive Load Test Circuit

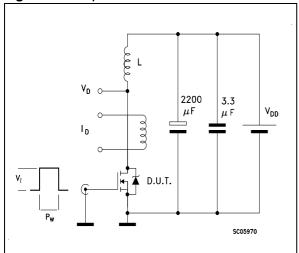


Fig. 3: Switching Times Test Circuits For Resistive Load

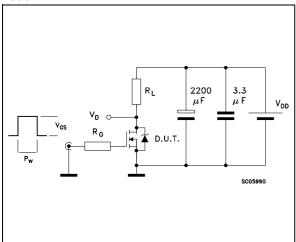


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

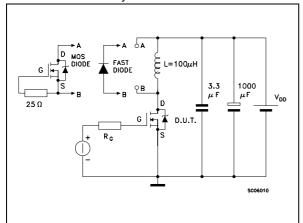


Fig. 2: Unclamped Inductive Waveform

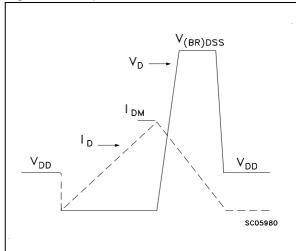
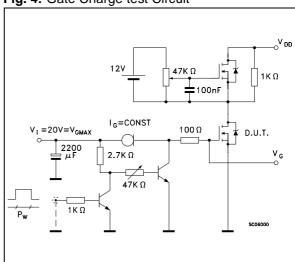


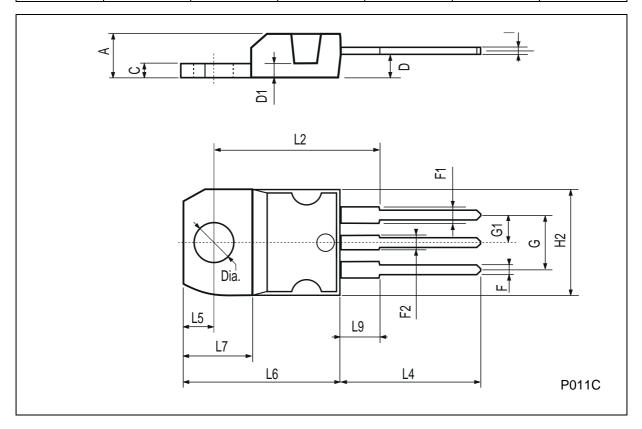
Fig. 4: Gate Charge test Circuit



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TO-220 MECHANICAL DATA

DIM.		mm			inch			
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
Α	4.40		4.60	0.173		0.181		
С	1.23		1.32	0.048		0.051		
D	2.40		2.72	0.094		0.107		
D1		1.27			0.050			
Е	0.49		0.70	0.019		0.027		
F	0.61		0.88	0.024		0.034		
F1	1.14		1.70	0.044		0.067		
F2	1.14		1.70	0.044		0.067		
G	4.95		5.15	0.194		0.203		
G1	2.4		2.7	0.094		0.106		
H2	10.0		10.40	0.393		0.409		
L2		16.4			0.645			
L4	13.0		14.0	0.511		0.551		
L5	2.65		2.95	0.104		0.116		
L6	15.25		15.75	0.600		0.620		
L7	6.2		6.6	0.244		0.260		
L9	3.5		3.93	0.137		0.154		
DIA.	3.75		3.85	0.147		0.151		



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